

Notice of References Cited

Application/Control No.

09/786,990

Applicant(s)/Patent Under
Reexamination
ONISHI ET AL.

Examiner

DEVONA E. FAULK

Art Unit

2614

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,370,253	04-2002	Onishi et al.	381/98
	B	US-			
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	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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